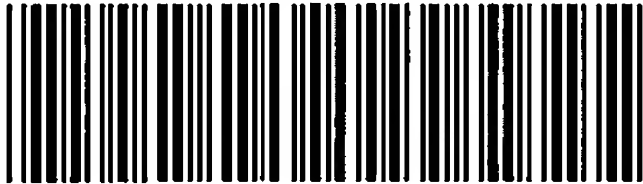


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/029,877	SIMEON ET AL.	
	Examiner	Art Unit	
	Jia W. Lu	2634	

SEARCHED			
Class	Subclass	Date	Examiner
375	340	3/22/2005	JL
375	526	3/22/2005	JL

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
375	340	3/22/2005	JL

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
US-PGPUB; USPAT; EPO;JAP;DERWENT;IBM_TDB	3/22/2005	JL
INVENTORSHIP	3/22/2005	JL